

Search Notes				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/721,326	SHIINA, MASAKI	
				Examiner	Art Unit	
				Emmanuel Sayoc	3746	

SEARCHED			
Class	Subclass	Date	Examiner
92	71X	12/20/05	(ES)
	165R		
	169,1		
92	177X		
417	269	12/20/05	(ES)
x	417	269	6/29/06 W.R
x	417	222.1	
x	92	71	
x	92	165R	
x	92	169,1	
x	92	177	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Same as above		6/29/06	W.R

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
92 - Lopez 417 - Freay	12/19/05	(ES)
See text search	12/20/05	(ES)
In addition: Inventor's and text search.	6/29/06	W.R